

Effects of interfacial oxide layer thickness and interface states on conversion efficiency of SnO₂/SiO₂/Si(N) solar cells

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Abstract. In this paper, we studied the effects of interfacial oxide layer thickness and interface state density on the open circuit voltage and efficiency of the SnO₂/SiO₂/Si (N) solar cells. The results obtained by numerical simulation using Matlab programs are presented and discussed. The SnO₂/SiO₂/Si (N) solar cells, in which the interfacial oxide layer thickness is optimized to 21 Å, have an average open circuit voltage of 0.62 V and a short circuit current of 36 mA/cm². The calculated conversion efficiency of the cells can be as high as 17.5 %.

Keywords: Solar cell, Heterostructure, Oxide layer, Efficiency, Simulation.

1. Introduction

There has been considerable interest in recent years directed toward the development of metal-insulator-semiconductor (MIS) solar cells. Very often in these structures, tin oxide (SnO₂), indium tin oxide (ITO), and zinc oxide (ZnO) were used in place of the metal electrode [1]. Among these, SnO₂ is chosen because of its high electrical conductivity [2] and its transparency in the visible and infrared light [3], therefore it acts as a window for sunlight. Further, its refractive index lies in between 1.9 and 2.0 and hence it can be used as an antireflection (AR) coating [4].

2. Results and discussion

A. Effect of the interfacial oxide layer thickness on the open circuit voltage of the SnO₂/SiO₂/Si(N) solar cells

The results of calculation of open circuit voltage V_{oc} as a function of δ for different values of Φ_0 are shown schematically in figure 1. The increase in open circuit voltage with increasing the interfacial layer thickness δ in the initial stages is due to reverse current (J_S) reduction and hence to the thermionic emission current reduction (J_{TE}) which is shown in figure 2.

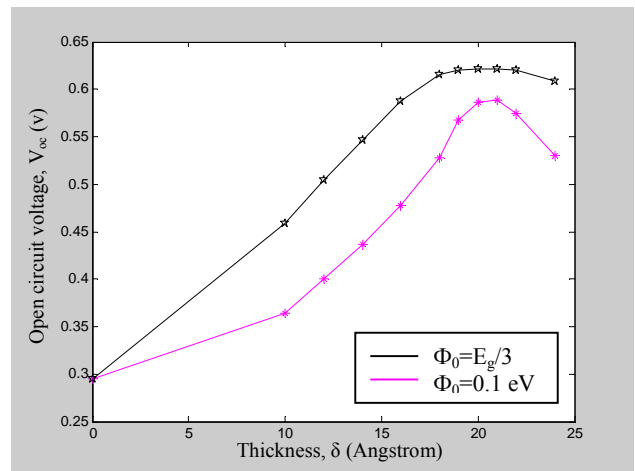


Figure 1. Variations of V_{oc} with interfacial oxide layer thickness δ at different values of Φ_0

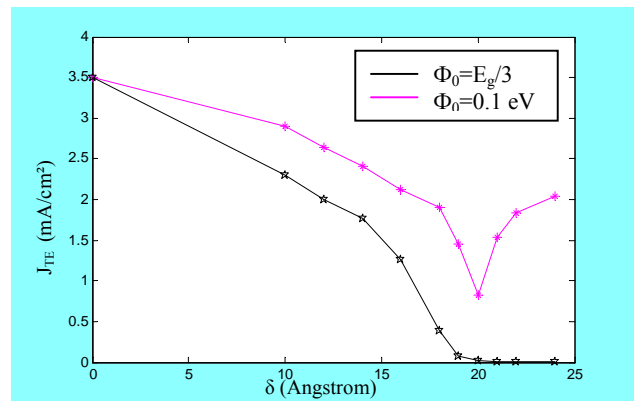


Figure 2. Variations of the thermionic emission current J_{TE} with interfacial oxide layer thickness δ at different values of Φ_0

B. Photovoltaic characteristics of SnO₂/SiO₂/Si(N) solar cell

The current–voltage characteristics of the cell under illumination are computed for different values of interfacial oxide (insulator) thickness δ and presented in figure 3.

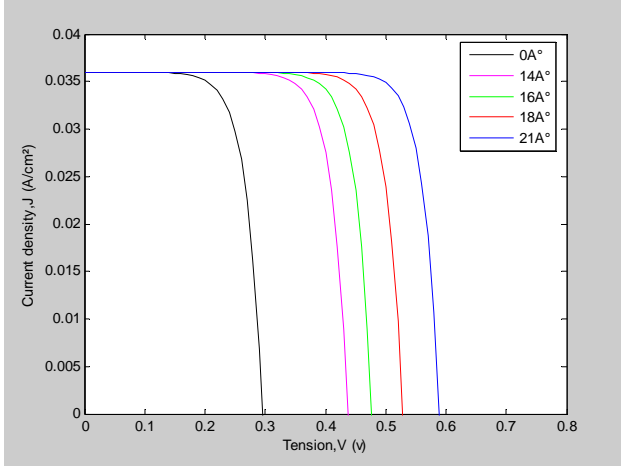


Figure 3. Illuminated J – V characteristics for the SnO₂/SiO₂/Si(N) solar cell at different values of insulator thickness δ when $\Phi_0=0.1$ eV under optimum conditions.

C. Effect of the interfacial oxide layer thickness on the efficiency of the SnO₂/SiO₂/Si(N) solar cells

The results of calculation of conversion efficiency of the cell for different values of the interfacial layer thickness for specific values of interface state density and Φ_0 are shown in figure 4. The efficiency initially increases with δ due to an increase in open circuit voltage V_{oc} . When $\Phi_0=0.1$ eV, the decrease in efficiency, after a certain optimum, is mainly due to a decrease in the fill factor FF for higher values of δ . In Table 1 we give the calculated values for fill factor FF for two cases: $\Phi_0=0.1$ eV and $\Phi_0=E_g/3$ eV.

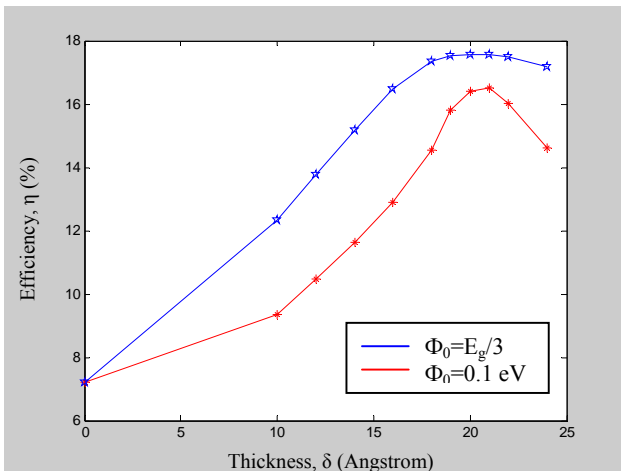


Figure 4. Variations of the efficiency with interfacial oxide layer thickness δ at different values of Φ_0

TABLE 1: The calculated values for fill factor FF for different values of the interfacial oxide layer thickness δ for specific values of Φ_0 , under optimum conditions.

δ (Å)	FF ($\Phi_0=0.1$ eV)	FF ($\Phi_0=E_g/3$ eV)
0	0.68	0.68
10	0.71	0.75
12	0.73	0.76
14	0.74	0.77
16	0.75	0.78
18	0.76	0.78
19	0.77	0.78
20	0.78	0.78
21	0.78	0.78
22	0.77	0.78
24	0.76	0.78

The improved fill factor and the increase in the solar conversion efficiency of the cells make such optimized oxide layers, important components in the solar cells fabrication. The SnO₂/SiO₂/Si (N) type solar cells can be made by a low cost processing like APCVD (Atmospheric pressure chemical vapour deposition) or Spray pyrolysis [2]. These cells can be used in the fabrication of solar panels as clean energy converters.

3. Conclusion

The inclusion of an interfacial oxide layer (SiO₂) between SnO₂ and Si leads to the improvement of the open circuit voltage and efficiency of the solar cells by reducing the dark current. Such improvement allows the use of the SnO₂/SiO₂/Si (N) type solar cells as clean, efficient and economical energy converters. The optimum oxide layer thickness for maximum efficiency is found to be 21 Å. The calculated efficiencies of the cells can be as high as 17.5 %. Combining the high–efficiency, lower cost processing, we believe the SnO₂/SiO₂/Si (N) type solar cells have good potential to meet the goal of large-scale terrestrial applications.

References

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